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(54) **Title:** METHOD OF CHARACTERIZING LAYER THICKNESS

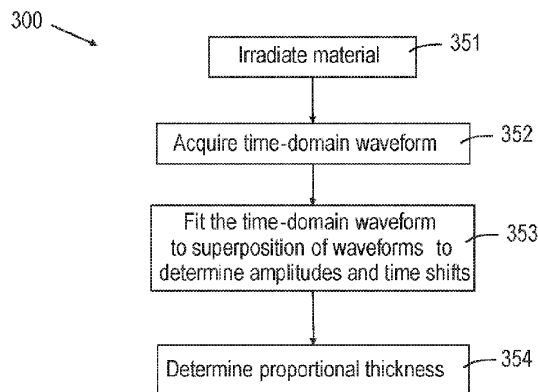


FIG. 2

(57) **Abstract:** A method of characterizing thickness of at least one layer of a material includes irradiating the material with a THz pulse such that at least a portion of the THz pulse is reflected from the material as a reflected THz signal; acquiring a time-domain waveform of the reflected THz signal; fitting the time-domain waveform to a superposition of waveforms to determine pluralities of amplitudes and time shifts where each waveform in the superposition of waveforms is a reference waveform scaled by an amplitude in the plurality of amplitudes and time shifted by a time shift in the plurality of time shifts; and determining a proportional thickness of at least one layer of the material from a corresponding difference between two time shifts in the plurality of time shifts.

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Declarations under Rule 4.17:

- *as to applicant's entitlement to apply for and be granted a patent (Rule 4.17(ii))*
- *as to the applicant's entitlement to claim the priority of the earlier application (Rule 4.17(iii))*

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